

Search Notes

Application/Control No.

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Examiner

David L. Lewis

Applicant(s)/Patent under
Reexamination

CHUI, CLARENCE

Art Unit

2629

SEARCHED

Class	Subclass	Date	Examiner
345	55-108	2/19/2008	DL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST SEARCH keywords and subclass; uspat, uspgpubs, epo, jpo, derwent, ibm; inventor name search	2/19/2008	DL